

EE412

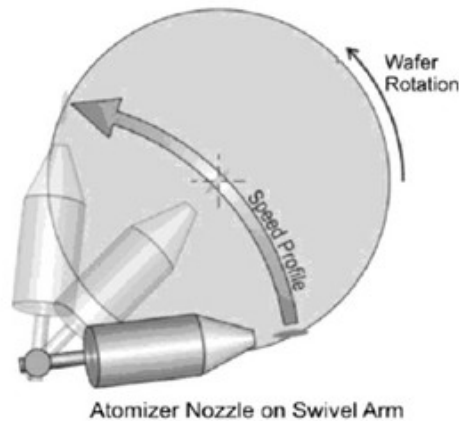
Deep Trench Spray Coating

Final Presentation

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Mentor : Jason Parker

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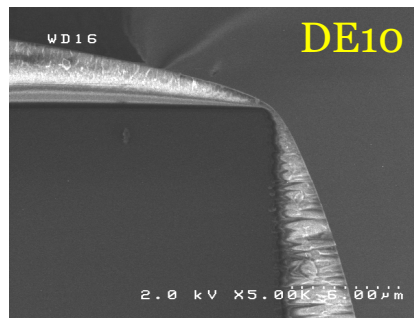
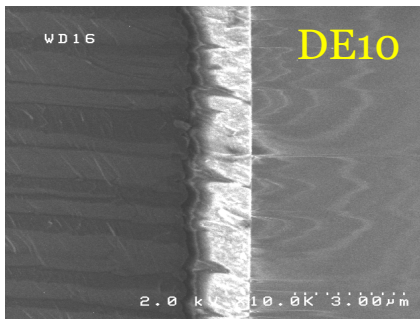
Introduction - EV101 Spraycoater



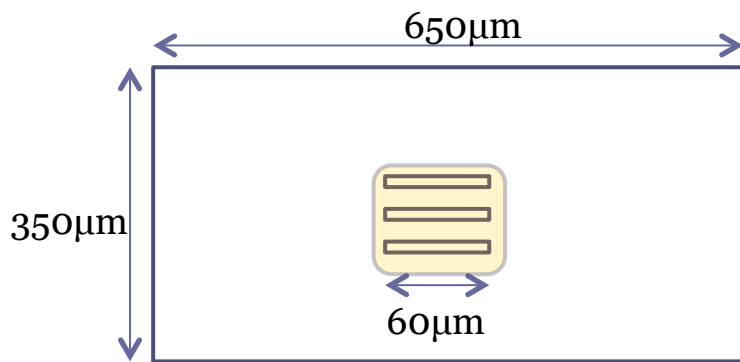
- Sprays a resist mixture using an ultrasonic nozzle. Typical droplet diameter $\sim 20\mu\text{m}$
- Low spin speeds (30rpm – 60rpm)
- Resist thickness is typically $10\mu\text{m}+$. Lower thickness possible if
 - Shallow features, or
 - Deep features but large areas to fill resist
- Can be used to protect sidewalls and corners with resist
- Uses relatively little resist material
- Both, planar and conformal coatings possible using different nozzles ('vortex' and 'accumist')

Sidewall
(250um deep)

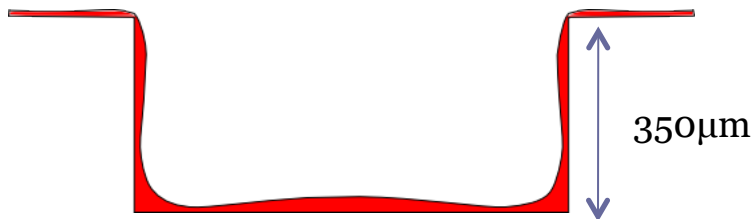
Corner



Objectives



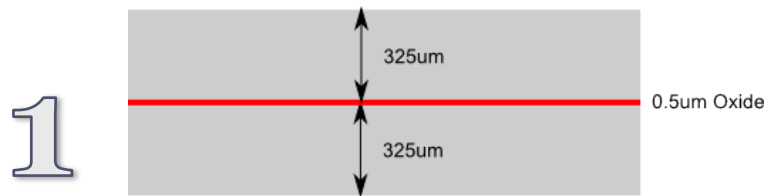
Top View



X-Section View

- Obtain a uniform coat of photoresist with thickness $< 3\mu\text{m}$ in the region of interest at the bottom of a $350\mu\text{m}$ deep $350\mu\text{m}$ x $650\mu\text{m}$ DRIE trench coated with silicon nitride
- Thickness variation $< 0.5\mu\text{m}$
- Expose test pattern in ASML using the MSI patch to test resolution limits
- Starting recipe was Pierres Ponce's P44

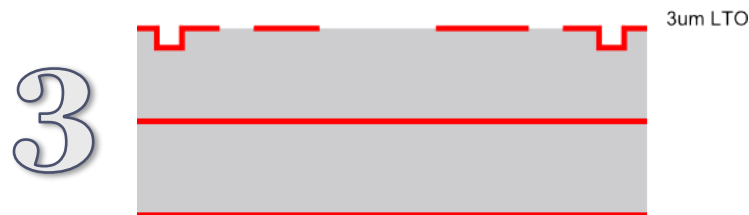
Wafer Preparation



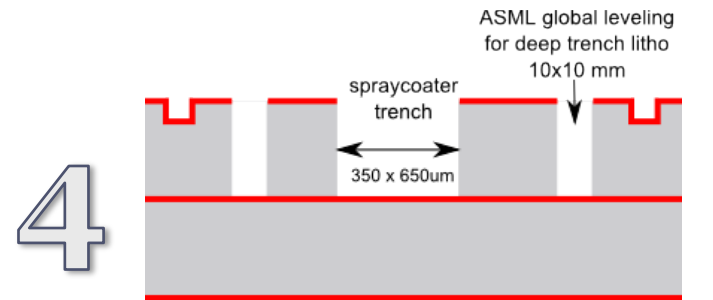
Fusion bond two R-prime wafers using the teflon jig with 0.5um oxide on handle. Exact procedure in wiki



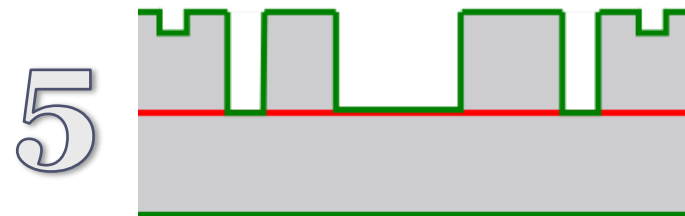
ASML alignment marks



Deposit 3um LTO and pattern trenches



Sts2 DRIE etch through top wafer



Strip masking oxide and BOX in 6:1 BOE. Deposit nitride

6 Before coating 20min in 9:1 piranha
Followed by HMDS prime in YES oven

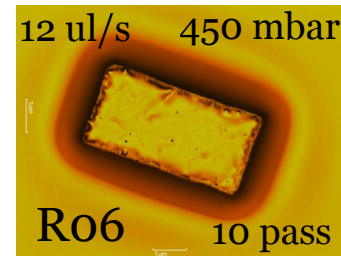
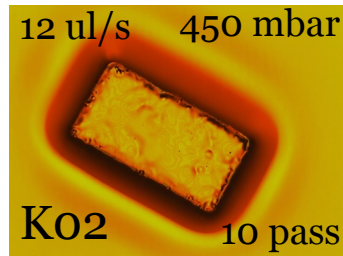
Parameters Explored

- Resist mixture consists of:
 - Photoresist SPR 220-7 (4.8% - 11.4%)
 - Low vapor pressure solvent Ethyl Lactate (25% - 45%)
 - High vapor pressure solvent MEK (remaining)
- Resist mixture dispense rate (3ul/s – 15ul/s)
- Nozzle pressure (300mbar – 900mbar)
- Number of passes (5 – 15)
- Velocity profile
- Heated chuck was used and set at 75C
- Total of 91 experiments exploring different combination of parameters. All results available on wiki

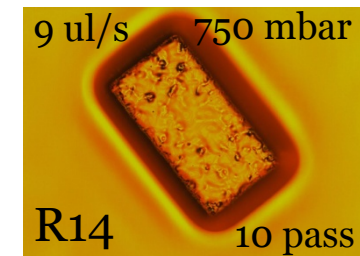
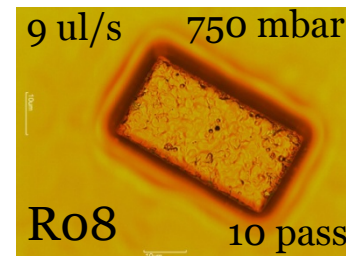
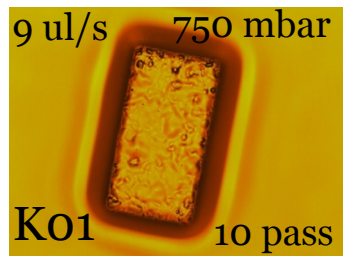
Repeatability

- Experimental results are repeatable

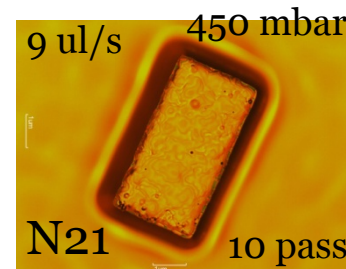
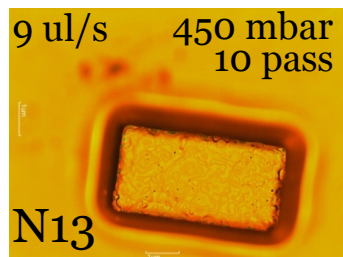
7.7% Resist
25% LVP



7.7% Resist
25% LVP



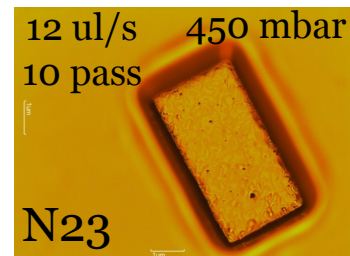
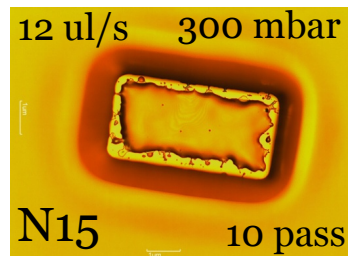
5% Resist
45% LVP



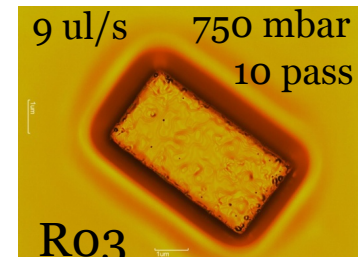
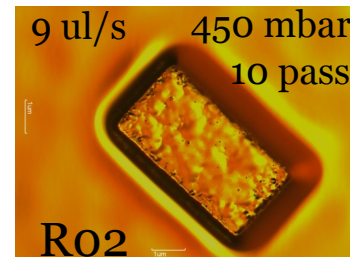
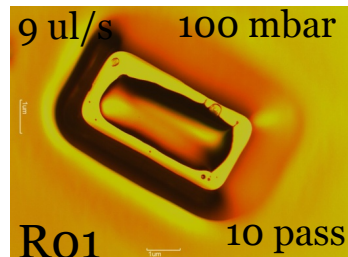
Effect of Pressure

- Higher pressure improves uniformity and causes less pooling of resist at the bottom of trench

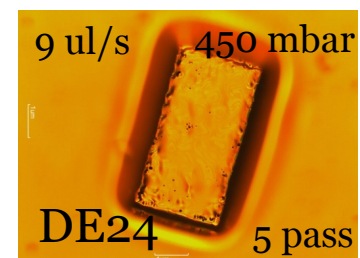
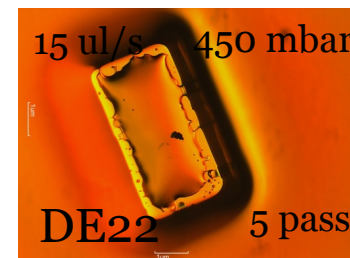
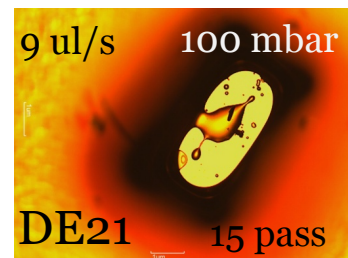
5% Resist
45% LVP



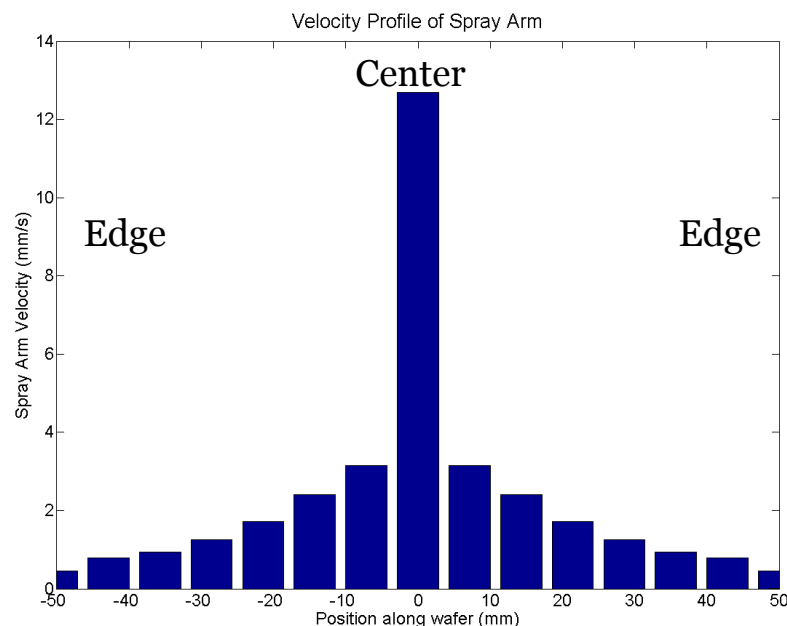
5% Resist
25% LVP



11.5% Resist
44.6% LVP

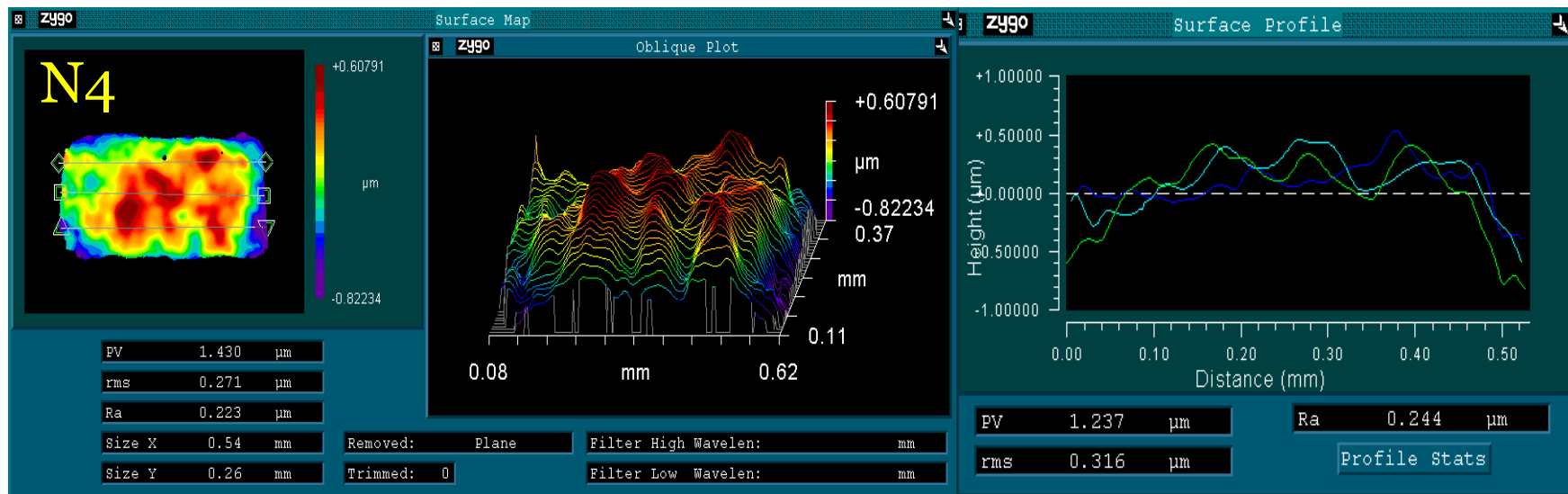


Velocity Profile



- Area to be coated is higher at edge as compared to center. Hence, velocity needs to be adjusted to obtain uniform coating thickness
- Velocity profile can be scaled to increase or decrease overall time per pass
- Scaling also changes dispense rate if thickness is to be kept constant
- Slow passes lead to less rough films. But can cause resist pooling due to large quantity of resist being dispensed

Zygo Results (Jason)



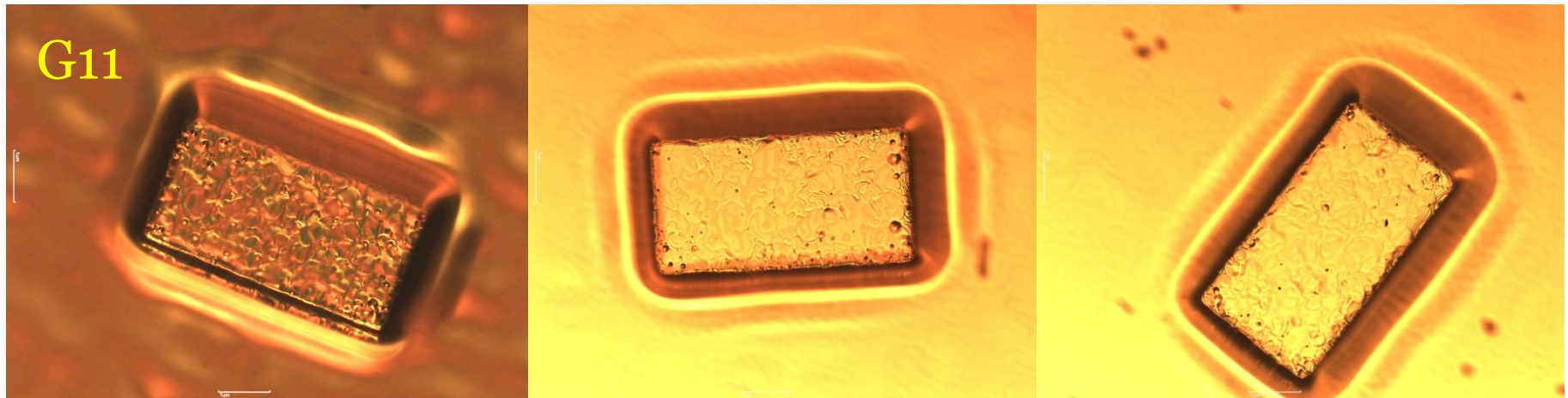
- Zygo measurements on select samples. Full results on wiki
- Samples coated with 300A of Aluminum
- Surface roughness for above sample:
 - $Ra = 0.223\mu\text{m}$
 - $RMS = 0.271\mu\text{m}$

Recipe Used For ASML Exposure Testing

Center

Mid

Edge

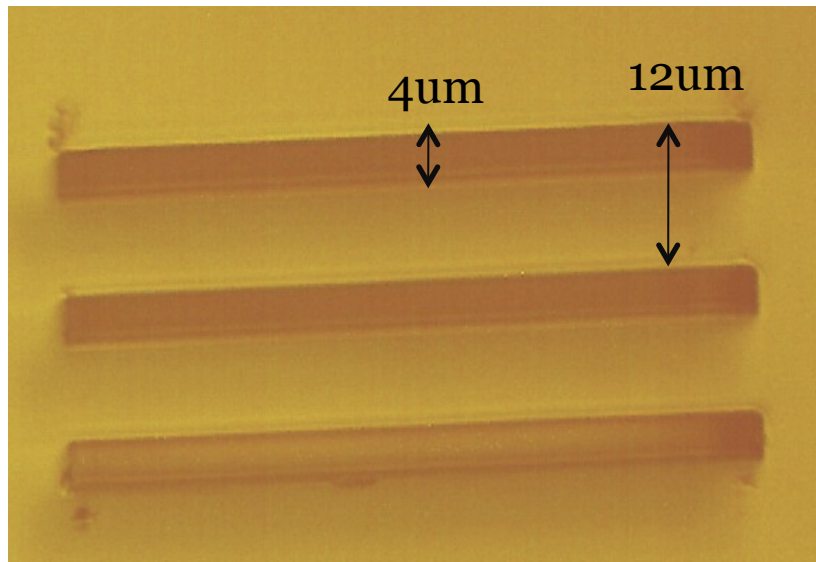


- Resist Mix : 5% SPR 220-7, 35% Ethyl Lactate, 60% MEK
- Dispense rate: 9ul/s, Pressure: 600mbar, Passes: 12

Deep Trench Lithography With ASML

- ASML in 'normal' mode
 - Cannot apply focus offsets of more than 30um
 - Global leveling is done at three points which are not user controllable. If deep features are present the wafer can get rejected
- ASML in special 'MSI' patch mode
 - Gives user control of level sensor locations. However need large area (10 x 10mm)
- Deep trench lithography possible if 3 large 10 x 10mm squares (GL openings) are etched to the same level as features to be exposed
- GL openings need to have low roughness

Exposure Testing with ASML



- 4um features could be resolved in the large 10mm x 10mm trenches up to 1mm from the trench walls
- Dose of 150mJ and 2min development cleared some of the features and not others. Over exposed wafer second time with 250mJ to clear resist from all areas
- Resist couldn't be cleared from smaller 350um x 650um trenches even after high energy dose (700mJ)
- Manual development in Headway for 2min – 5min

Conclusions

- Developed a spraycoat recipe for coating resist in 350x650 wide and 350um deep cavities
- Final recipe
 - Resist mix: 5% SPR 220-7, 35% Ethyl Lactate and 60% MEK
 - Dispense rate: 9ul/s
 - Pressure: 600 mbar
 - Passes: 12
- Resist thickness in the central 100um x 100um area at the bottom of trench $2.7\mu\text{m} \pm 0.3\mu\text{m}$
- Tested recipe for deep trench lithography applications with ASML and was able to resolve 4um features in large areas

Acknowledgements

- Jason Parker, Pierre Ponce, J Provine
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